

# LH531000B-S

CMOS 1M (128K × 8) 3 V-Drive MROM

## FEATURES

- 131,072 words × 8 bit organization
- Access time: 500 ns (MAX.)
- Power consumption:
  - Operating: 64.8 mW (MAX.)
  - Standby: 108 µW (MAX.)
- Mask-programmable control pin:  
Pin 20 = CE/OE/OE
- Static operation
- Three-state outputs
- Low power supply: 2.6 V to 3.6 V
- Package: 28-pin, 450-mil SOP

## DESCRIPTION

The LH531000B-S is a mask-programmable ROM organized as 131,072 × 8 bits. It is fabricated using silicon-gate CMOS process technology.

## PIN CONNECTIONS

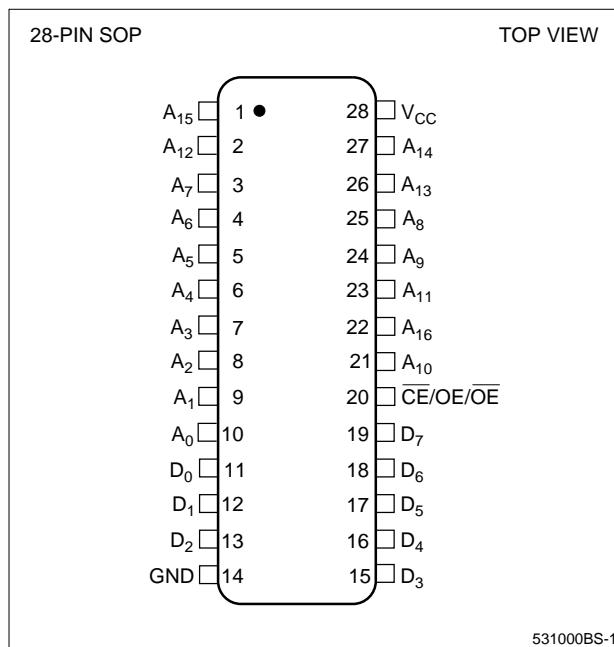


Figure 1. Pin Connections for DIP Package

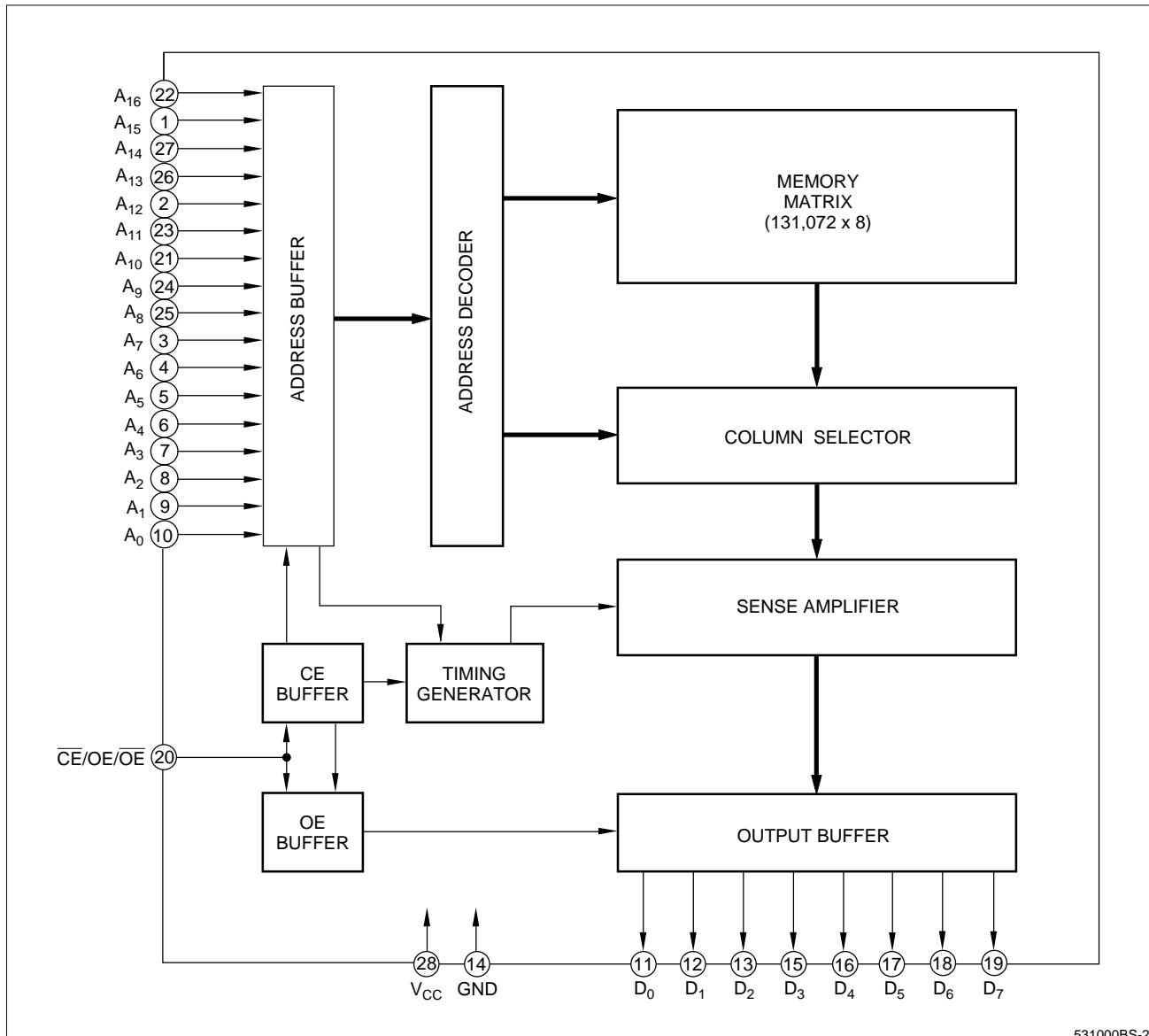


Figure 2. LH531000B-S Block Diagram

**PIN DESCRIPTION**

SIGNAL	PIN NAME	NOTE
A <sub>0</sub> – A <sub>16</sub>	Address input	
D <sub>0</sub> – D <sub>7</sub>	Data output	
CE/OE/OE	Chip Enable input or Output Enable input	1

**NOTE:**

1. Active level of CE/OE/OE is mask-programmable.

SIGNAL	PIN NAME	NOTE
V <sub>CC</sub>	Power supply (2.6 V to 3.6 V)	
GND	Ground	

**TRUTH TABLE**

<b>CE</b>	<b>OE/OE</b>	<b>MODE</b>	<b>SUPPLY CURRENT</b>
H	-	High-Z	Standby
L	-	Output	Operating
-	L/H	High-Z	Operating
-	H/L	Output	

**ABSOLUTE MAXIMUM RATINGS**

<b>PARAMETER</b>	<b>SYMBOL</b>	<b>RATING</b>	<b>UNIT</b>
Supply voltage	V <sub>CC</sub>	-0.3 to +7.0	V
Input voltage	V <sub>IN</sub>	-0.3 to V <sub>CC</sub> + 0.3	V
Output voltage	V <sub>OUT</sub>	-0.3 to V <sub>CC</sub> + 0.3	V
Operating temperature	T <sub>OPR</sub>	0 to +70	°C
Storage temperature	T <sub>STG</sub>	-65 to +150	°C

**RECOMMENDED OPERATING CONDITIONS (T<sub>A</sub> = 0°C to +70°C)**

<b>PARAMETER</b>	<b>SYMBOL</b>	<b>MIN.</b>	<b>TYP.</b>	<b>MAX.</b>	<b>UNIT</b>
Supply voltage	V <sub>CC</sub>	2.6		3.6	V

**DC CHARACTERISTICS (V<sub>CC</sub> = 2.6 V to 3.6 V, T<sub>A</sub> = 0°C to +70°C)**

<b>PARAMETER</b>	<b>SYMBOL</b>	<b>CONDITIONS</b>	<b>MIN.</b>	<b>TYP.</b>	<b>MAX.</b>	<b>UNIT</b>	<b>NOTE</b>
Input 'Low' voltage	V <sub>IL</sub>		-0.3		0.4	V	
Input 'High' voltage	V <sub>IH</sub>		0.8 × V <sub>CC</sub>		V <sub>CC</sub> + 0.3	V	
Output 'Low' voltage	V <sub>OL</sub>	I <sub>OL</sub> = 400 μA			0.4	V	
Output 'High' voltage	V <sub>OH</sub>	I <sub>OH</sub> = -100 μA	0.8 × V <sub>CC</sub>			V	
Input leakage current	I <sub>LI</sub>	V <sub>IN</sub> = 0 V to V <sub>CC</sub>			10	μA	
Output leakage current	I <sub>LO</sub>	V <sub>OUT</sub> = 0 V to V <sub>CC</sub>			10	μA	1
Operating current	I <sub>CC</sub>	t <sub>RC</sub> = 500 ns			18	mA	2
Standby current	I <sub>SB</sub>	CE = V <sub>CC</sub> - 0.2 V			30	μA	
Input capacitance	C <sub>IN</sub>	f = 1 MHz			10	pF	
Output capacitance	C <sub>OUT</sub>	T <sub>A</sub> = 25°C			10	pF	

**NOTE:**

1. CE/OE = V<sub>IH</sub>, OE = V<sub>IL</sub>
2. Outputs open

**AC CHARACTERISTICS (V<sub>CC</sub> = 2.6 V to 3.6 V, T<sub>A</sub> = 0°C to +70°C)**

<b>PARAMETER</b>	<b>SYMBOL</b>	<b>MIN.</b>	<b>MAX.</b>	<b>UNIT</b>	<b>NOTE</b>
Read cycle time	t <sub>RC</sub>	500		ns	
Address access time	t <sub>AA</sub>		500	ns	
Chip enable access time	t <sub>ACE</sub>		500	ns	
Output enable delay time	t <sub>OE</sub>		200	ns	
Output hold time	t <sub>OH</sub>	10		ns	
CE to output in High-Z	t <sub>CHZ</sub>			ns	
OE to output in High-Z	t <sub>OHZ</sub>			ns	1

**NOTE:**

1. This is the time required for the output to become high-impedance.

## AC TEST CONDITIONS

PARAMETER	RATING
Input voltage amplitude	0.4 V to $(0.8 \times V_{CC})$ V
Input rise/fall time	10 ns
Input/output reference level	1.5 V
Output load condition	1 TTL + 100 pF

## CAUTION

To stabilize the power supply, it is recommended that a high-frequency bypass capacitor be connected between the  $V_{CC}$  pin and the GND pin.

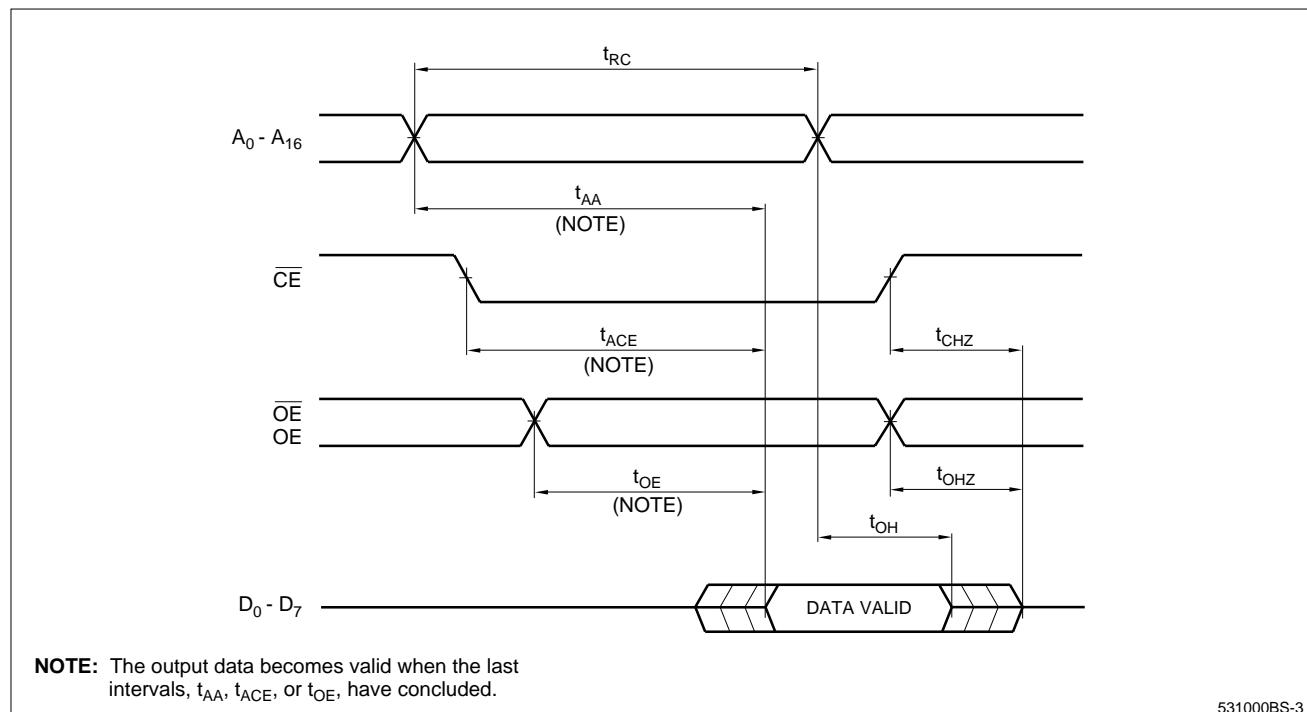
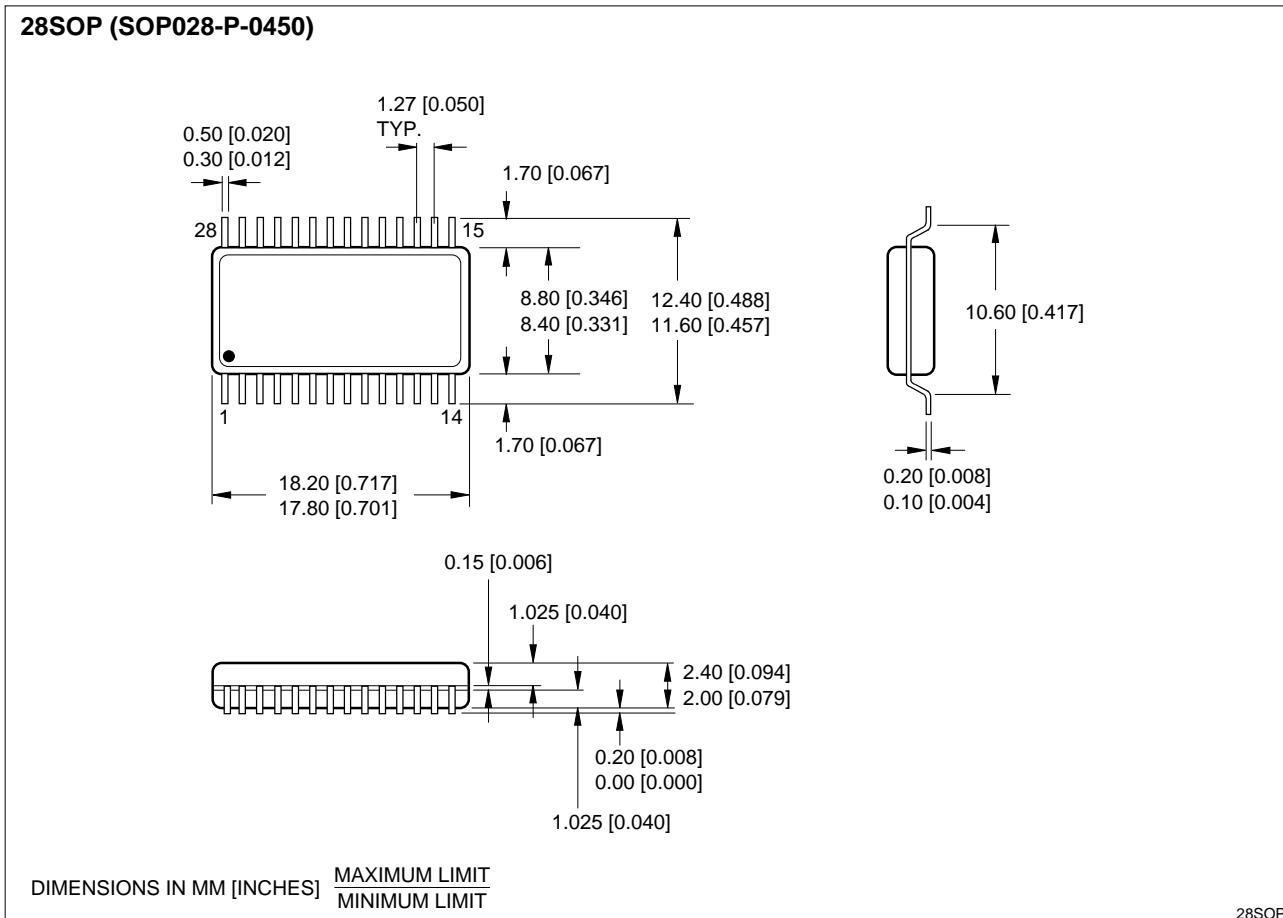


Figure 3. Timing Diagram

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## PACKAGE DIAGRAM

**28-pin, 450-mil SOP**

## ORDERING INFORMATION

Device Type	Package	Low-Voltage Operation
LH53100B	N	- S
		Low-Voltage Operation
		28-pin, 450-mil SOP (SOP028-P-0450)
		CMOS 1M (128K x 8) Mask-Programmable ROM

**Example:** LH53100BN-S (CMOS 1M (128K x 8) Mask-Programmable ROM, Low-Voltage Operation, 28-pin, 450-mil SOP)

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